

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of Applicants:

Date: October 26, 2009

Beaman et al.

Group Art Unit: 2829

Serial No.: 09/251,988

Examiner: J. M. Hollington

Filed: February 17, 1999

Docket No.: YOR91999088US1

For: STRUCTURAL DESIGN AND PROCESSES TO CONTROL PROBE
POSITION ACCURACY IN A WAFER TEST PROBE ASSEMBLY

Commissioner for Patents

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